

TWP Thermal wireless profiler for wafers

TWP thermal wireless profiler is a flexible tool to measure temperatures during semiconductor wafer production processes

It is based on a thermocouple conditioning unit, available in 8 or 16 channels version, which is connected to a data display and recording unit implemented on a hand held computer via a Bluetooth wireless transmission.

The instrument can be used with thermocouple equipped wafers and is capable of different data display options such as table, map and single channel.

Data logging is performed on a Secure Digital memory card, and files can be directly imported by the most common spreadsheet programs.

System can be easily used and configured and features many different options and accessories.



Specifications

Channels	8 or 16 (TWP8 - TWP16) thermocouples
Thermocouple type	K, J, R, T, N - Standard is K, other types on request
Clean room compatibility	Class 1 clean room compatible
Control	Palm-OS hand held computer and separated amplifier
Type of measure	Single point, list and wafer map
Data logging	SD memory card - .csv file recording
Accuracy	+/- 0.1 % on full scale
Connections	EIA type 37 points compensated connector
Battery	2.5 hours (16 points unit)
Dimensions	Amplifier: 200 X 115 X 50 mm
Accessories	AC adapters for amplifier and terminal SD memory card reader - USB cable PC profiling software (optional)

(Specifications are subject to change without any obligation on the part of manufacturer)